

FUJITSU

256K x 8 CMOS SRAM MODULE

MB85403A-40
MB85403A-50TS261-A88Y
Nov. 1988CMOS 262,144 Words x 8-Bit STATIC
RANDOM ACCESS MEMORY MODULE

The Fujitsu MB85403A is a fully decoded, CMOS static random access memory module consists of eight MB81C81A devices mounted on a 44-pin ceramic board. Organized as eight 256K x 1 devices, the MB85403 is optimized for those applications requiring high speed, high performance, large memory storage, and high density.

- Organized as 262,144 x 8-bit Words
- Memory : MB81C81A, 8 pcs
- Access Time : 40 ns max (MB85403A-40)
50 ns max (MB85403A-50)
- Low Power Dissipation
 - Standby: 660 mW max (CMOS level)
1320 mW max (TTL level)
 - Active : 5280 mW max
- Single +5V Power Supply, $\pm 10\%$ Tolerance
- Automatic Power Down
- Dual Chip Select (x8 or x4 organization)
- TTL Compatible Input/Output Pins
- 3-State Output
- 44-Pin 100 MIL Ceramic Twin SIP (TSIP)

ABSOLUTE MAXIMUM RATING (See NOTE.)

Rating	Symbol	Value	Unit
Supply Voltage	V _{CC}	-0.5 to +7.0	V
Input Voltage	V _{IN}	-3.5 to +7.0	V
Output Voltage	V _{OUT}	-0.5 to +7.0	V
Short Circuit Output Current	I _{OUT}	± 20	mA
Power Dissipation	P _D	8.0	W
Temperature under Bias	T _{BIAS}	-10 to +85	°C
Storage Temperature	T _{STG}	-65 to +150	°C

NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

PRELIMINARY

CERAMIC PACKAGE
MTP-44C-C02PIN ASSIGNMENT
TOP VIEW

GND	1	□	44	VCC
DOUT0	2	□	43	DOUT7
DIN0	3	□	42	DIN7
A16	4	□	41	A0
A17	5	□	40	A1
A13	6	□	39	A2
GND	7	□	38	A3
DOUT1	8	□	37	DOUT6
DIN1	9	□	36	DIN6
A12	10	□	35	A4
A11	11	□	34	A7
NC	12	□	33	/WE
/CSA	13	□	32	/CSB
DOUT2	14	□	31	DOUT5
DIN2	15	□	30	DIN5
A14	16	□	29	GND
A15	17	□	28	A6
A10	18	□	27	A5
A9	19	□	26	A8
DOUT3	20	□	25	DOUT4
DIN3	21	□	24	DIN4
VCC	22	□	23	GND

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields. However, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high impedance circuit.

DataSheet

6



MB85403A-40
MB85403A-50

Fig. 1 - BLOCK DIAGRAM

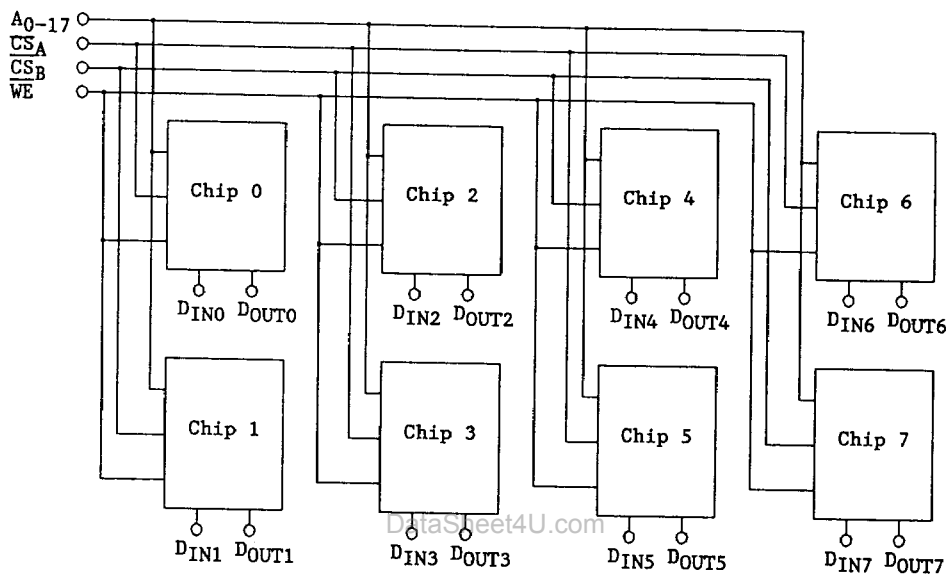
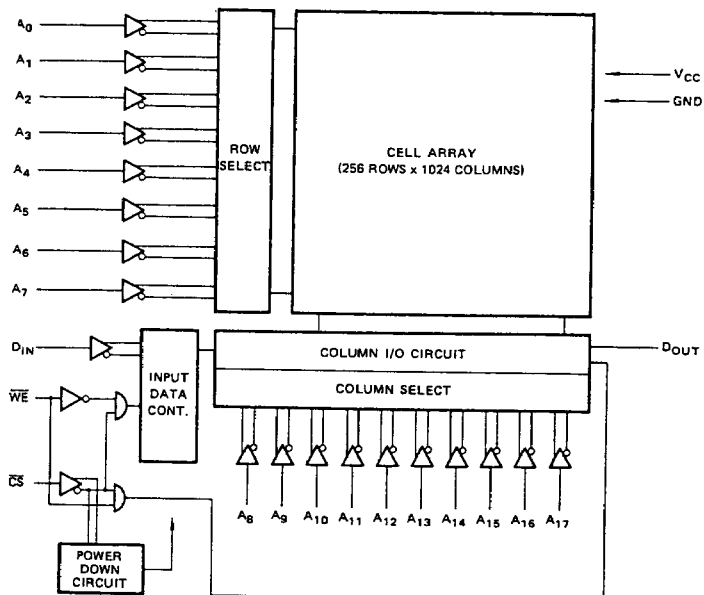


Fig. 2 - BLOCK DIAGRAM for EACH MEMORY



6



MB85403A-40
MB85403A-50

CAPACITANCE ($T_A=25^\circ\text{C}$, $f=1\text{MHz}$)

Parameter	Symbol	Typ	Max	Unit
Input Capacitance (except \overline{CS}_A , \overline{CS}_B)	C_{IN}		100	pF
Input Capacitance ($\overline{CS}_A+\overline{CS}_B$)	C_{CS}		120	pF
Output Capacitance	C_{OUT}		20	pF

FUNCTIONAL TRUTH TABLE

MODE	ADDRESS	\overline{CS}_A	\overline{CS}_B	\overline{WE}	INPUT	OUTPUT	POWER
STANDBY	DON'T CARE	V_{IH}	V_{IH}	DON'T CARE	HIGH-Z	HIGH-Z	STANDBY
WRITE	VALID	V_{IL}	V_{IL}	V_{IL}	D_{IN}	HIGH-Z	ACTIVE
READ	VALID	V_{IL}	V_{IL}	V_{IH}	HIGH-Z	D_{OUT}	ACTIVE

RECOMMENDED OPERATING CONDITIONS

(Referenced to GND)

Parameter	Symbol	Value			Unit
		Min	Typ	Max	
Supply Voltage	V_{CC}	4.5	5.0	5.5	V
Supply Voltage	GND		0		V
Operating Temperature Range	T_A	0	25	70	$^\circ\text{C}$

6



FUJITSU

MB85403A-40

MB85403A-50

DC CHARACTERISTICS

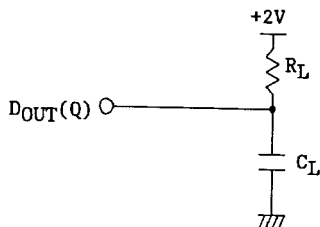
(Recommended operating conditions unless otherwise noted)

Parameter (conditions)	Symbol	Value			Unit
		Min	Typ	Max	
INPUT LEAKAGE CURRENT ($V_{IN}=0V$ to V_{CC})	I_{LI}	-80		80	μA
OUTPUT LEAKAGE CURRENT ($CS=V_{IH}$, $V_{OUT}=0V$ to V_{CC})	I_{LO}	-50		50	μA
STANDBY POWER SUPPLY CURRENT	CMOS level			120	mA
	TTL level			240	mA
ACTIVE POWER SUPPLY CURRENT ($CS=V_{IL}$, $I_{OUT}=0mA$)	MB85403A-40			960	mA
	MB85403A-50			800	
PEAK POWER ON SUPPLY CURRENT ($CS=$ Lower of V_{CC} , or V_{IH})	I_{PO}			240	mA
Input High Level	V_{IH}	2.2		6.0	V
Input Low Level *1	V_{IL}	-0.5		0.8	V
OUTPUT HIGH LEVEL ($I_{OH}=-4mA$)	V_{OH}	2.4			V
OUTPUT LOW LEVEL ($I_{OL}=16mA$)	V_{OL}			0.4	V

Note: *1 -3.0V min. for pulse width less than 20ns.

Fig. 3 - AC TEST CONDITIONS

- Input Pulse Levels : 0.6V to 2.4V
- Input Rise and Fall Times : 5ns
- Timing Reference Levels : $V_{IL}/V_{OL}=0.8V$, $V_{IH}/V_{OH}=2.2V$
- Output Load :



	R_L	C_L
Load I	100 Ω	30pF
Load II	100 Ω	5pF

www.DataSheet4U.com



FUJITSU MB85403A-40
MB85403A-50

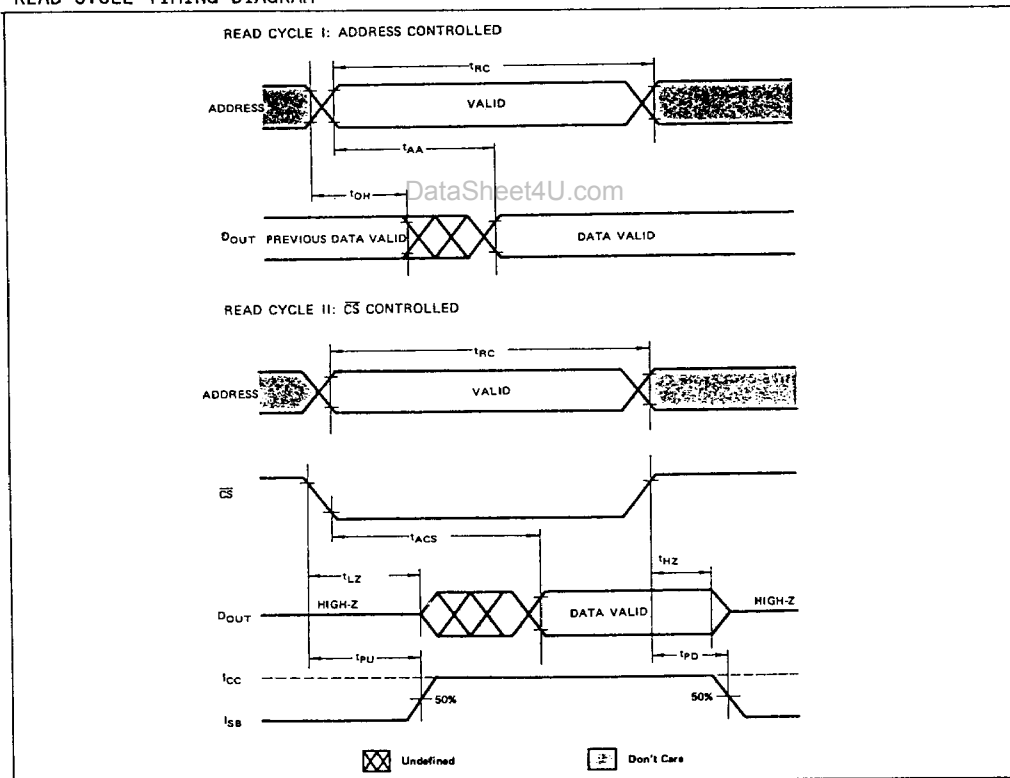
AC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.)

READ CYCLE *1

Parameter	Symbol	MB85403A-40		MB85403A-50		Unit
		Min	Max	Min	Max	
Read Cycle Time *2	t_{RC}	40		50		ns
Address Access Time	t_{AA}		40		50	ns
CS Access Time *3	t_{ACS}		40		50	ns
Output Hold from Address Change	t_{OH}	5		5		ns
CS to Output Low-Z *4*5	t_{LZ}	5		5		ns
CS to Output High-Z *4*5	t_{HZ}	0	25	0	30	ns
Power Up from CS	t_{PU}	0		0		ns
Power Down from CS	t_{PD}		40		50	ns

READ CYCLE TIMING DIAGRAM *1



Note: *1 \overline{WE} is high during Read cycle.

*2 Device is continuously selected, $\overline{CS}=V_{IL}$.

*3 Address valid prior to or coincident with \overline{CS} transition low.

*4 Transition is measured at the point of $\pm 500mV$ from steady state voltage.

*5 This parameter is specified with Load II in Fig. 3.



FUJITSU MB85403A-40
MB85403A-50

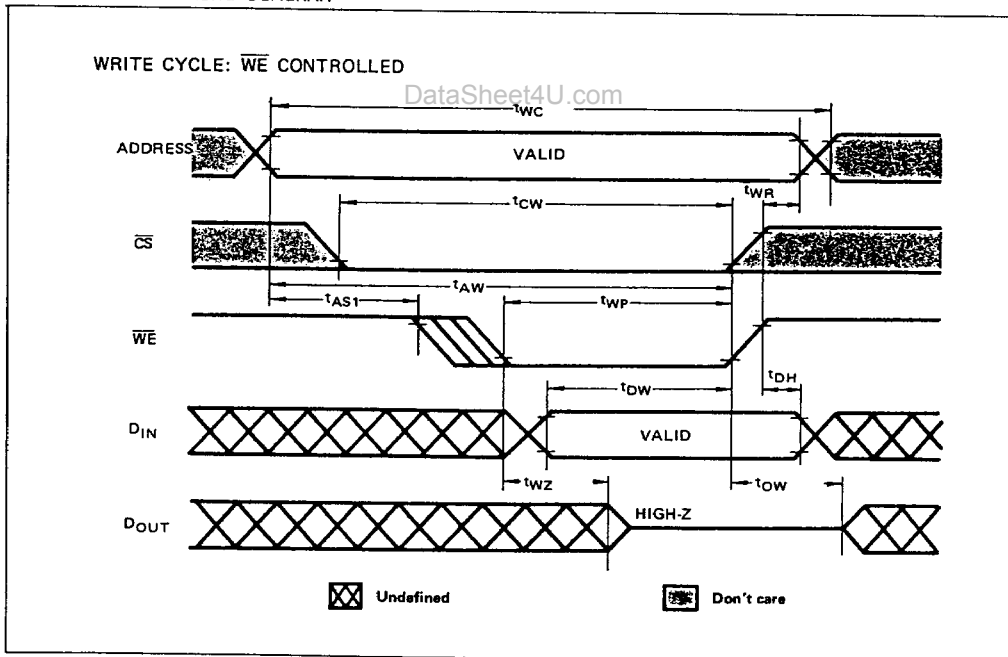
AC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.)

WRITE CYCLE *1

Parameter	Symbol	MB85403A-40		MB85403A-50		Unit
		Min	Max	Min	Max	
Write Cycle Time *2	t_{WC}	40		50		ns
Address Valid to End of Write	t_{AW}	35		45		ns
CS to End of Write	t_{CW}	35		45		ns
Data Valid to End of Write	t_{DW}	25		30		ns
Data Hold Time	t_{DH}	0		0		ns
Write Pulse Width	t_{WP}	25		30		ns
Address Setup Time	t_{AS1}	5		5		ns
	t_{AS2}	0		0		ns
Write Recovery Time	t_{WR}	5		5		ns
Output High-Z from \overline{WE} *3*4	t_{WZ}	0	25	0	30	ns
Output Low-Z from \overline{WE} *3*4	t_{OZ}	0		0		ns

WRITE CYCLE TIMING DIAGRAM



Note: *1 If \overline{CS} goes high simultaneously with \overline{WE} high, the output remains in high impedance state.

*2 All write cycle are determined from last address transition to the first address transition of the next address.

*3 Transition is measured at the point of $\pm 500\text{mV}$ from steady state voltage.

*4 This parameter is specified with Load II in Fig. 3.



FUJITSU

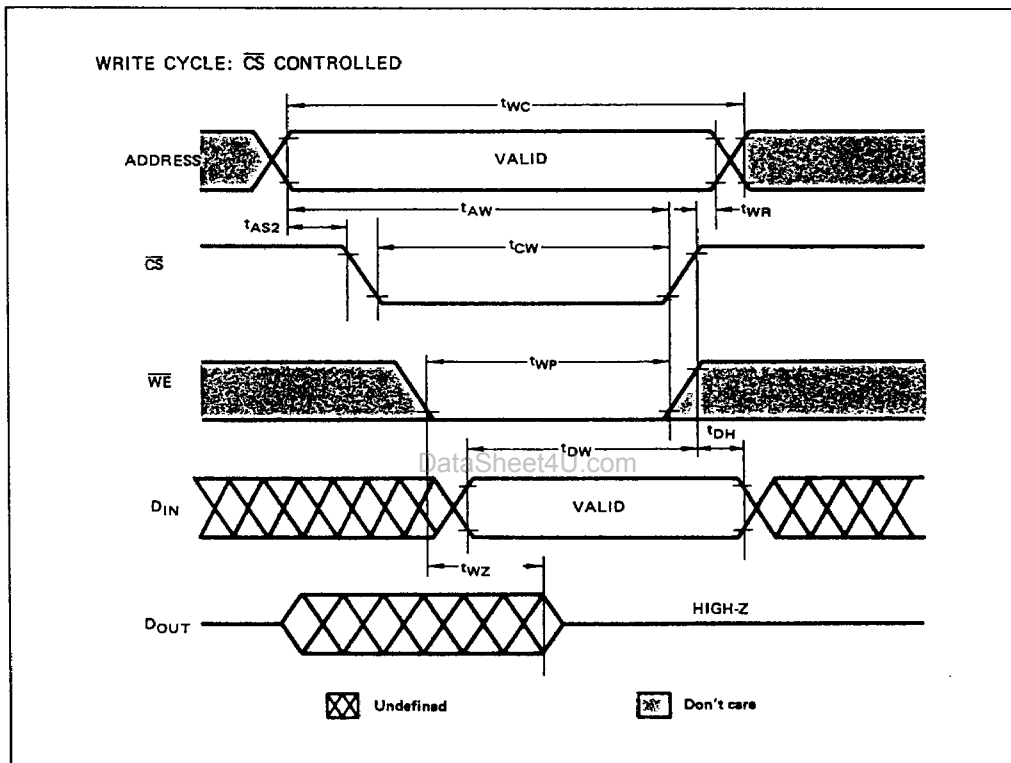
MB85403A-40

MB85403A-50

AC CHARACTERISTICS (Continued)

(At recommended operating conditions unless otherwise noted.)

WRITE CYCLE TIMING DIAGRAM

Note: *1 \overline{CS} or \overline{WE} must be high during address transitions.

*2 All write cycle are determined from last address transition to the first address transition of the next address.



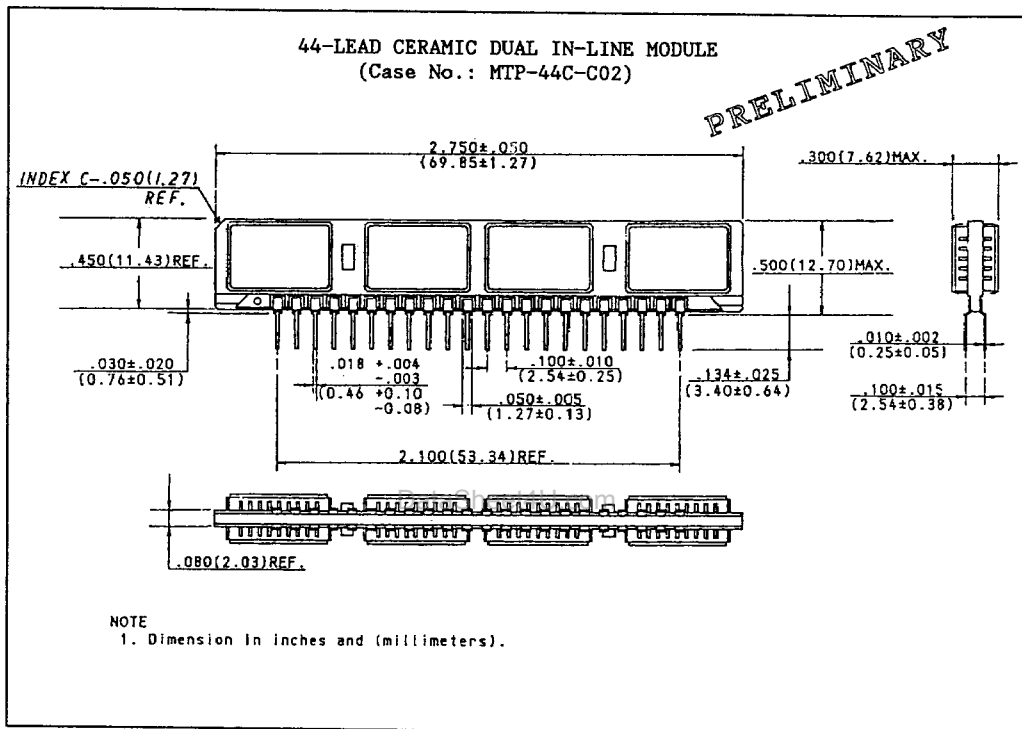
FUJITSU

MB85403A-40

MB85403A-50

PACKAGE DIMENSIONS

(Suffix: CVCT)



6